**國立臺灣科技大學貴儀中心樣品檢測申請單**

**(NTUST XPS Analysis Request Form)**

 申請日期(Date): 年(Y) 月(M) 日(D) 預約序號(Reservation Number):

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| 申請人(Name): 服務單位(Company/Lab): 聯絡電話(Phone): 分機(Ext): 手機(Cell Phone): 電子信箱(e-mail): 樣品件數(Number of samples): \_\_\_\_\_\_\_\_ |
| **樣品資訊 (Sample information)**若因填寫不確實導致機台損壞，將視情況求償。If the machine is damaged due to inaccurate filling, compensation will be made depending on the situation. |
| 序號(Serial Number) | 1 | 2 | 3 | 4 | 5 |
| 品名(Sample Name) |  |  |  |  |  |
| 化學組成(Chemical Components) |  |  |  |  |  |
| 表面結構(Rough/Smooth) |  |  |  |  |  |
| 樣品型態(Type) | □薄膜(Film)□塊材(Bulk){整體厚度<6mm (thickness)： mm}□粉末(Powder)1.壓銦片(Press into In)2.壓錠(tableting) | □薄膜(Film)□塊材(Bulk){整體厚度<6mm (thickness)： mm}□粉末(Powder)1.壓銦片(Press into In)2.壓錠(tableting) | □薄膜(Film)□塊材(Bulk){整體厚度<6mm (thickness)： mm}□粉末(Powder)1.壓銦片(Press into In)2.壓錠(tableting) | □薄膜(Film)□塊材(Bulk){整體厚度<6mm (thickness)： mm}□粉末(Powder)1.壓銦片(Press into In)2.壓錠(tableting) | □薄膜(Film)□塊材(Bulk){整體厚度<6mm (thickness)： mm}□粉末(Powder)1.壓銦片(Press into In)2.壓錠(tableting) |
| 導電性(conductivity) | □好Good□差Poor | □好Good□差Poor | □好Good□差Poor | □好Good□差Poor | □好Good□差Poor |
| 具強磁性(Strong magnetic) | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N |
| 具揮發性(volatile) | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N |
| 具毒性(toxic) | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N |
| 具輻射性(radioactive) | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N | □是Y □否N |
| **委測項目(Test Item)** |
| 1.表面清潔(Preclean) | □是Y, ( \_\_\_\_kV, \_\_\_\_mm\*\_\_\_\_mm, \_\_\_\_\_\_\_\_\_sec/min) | □是Y, ( \_\_\_\_kV, \_\_\_\_mm\*\_\_\_\_mm, \_\_\_\_\_\_\_\_\_sec/min) | □是Y, ( \_\_\_\_kV, \_\_\_\_mm\*\_\_\_\_mm, \_\_\_\_\_\_\_\_\_sec/min) | □是Y, ( \_\_\_\_kV, \_\_\_\_mm\*\_\_\_\_mm, \_\_\_\_\_\_\_\_\_sec/min) | □是Y, ( \_\_\_\_kV, \_\_\_\_mm\*\_\_\_\_mm, \_\_\_\_\_\_\_\_\_sec/min) |
| 2.全能譜掃描(Survey) | □是YRange: | □是YRange: | □是YRange: | □是YRange: | □是YRange: |
| 3.單元素能譜圖(Multiplex) | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): |
| 4.元素線掃描(Line Scan) | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): |
| 5.元素影像分析(Map Scan) | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): | 元素(Elements): |
| 6.成分縱深分析(Depth Profile) | Ion Gun :□Ar+ □C60+元素(Elements): | Ion Gun :□Ar+ □C60+元素(Elements): | Ion Gun :□Ar+ □C60+元素(Elements): | Ion Gun :□Ar+ □C60+元素(Elements): | Ion Gun :□Ar+ □C60+元素(Elements): |
| 7.紫外光電子能譜-UPS(Sample Ω < 60 Ω) | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω |
| 8.低能量反光電子能譜- LEIPS(Sample Ω < 60 Ω) | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω | □是Y, \_\_\_\_\_\_Ω |
| 其他樣品與測試條件說明 (Explanation of sample):(例如：標明要分析元素軌域或範圍、分析區域標示、正反面標示、分析條件加強說明、樣品是否攜回)(e.g.: Indicate the orbital or range of elements to be analyzed, mark the analysis area, mark the front and back sides, analysis conditions, whether the sample is retained) |
| ◎本表需於預約完成日起一週內以E-mail提供或與儀器操作員聯繫何如紘(02)2733-3141#5423，否則該次預約將被取消。(This form must be provided by E-mail (hjh@mail.ntust.edu.tw) or contact the instrument operator Ju-Hung Ho (02) 2733-3141#5423 within one week after the appointment is completed, otherwise the appointment will be cancelled.)◎樣品的數據名稱皆以申請書上樣品編碼1、2、3…命名。(The data names of the samples are named after the sample codes 1, 2, 3... on the application form.)◎若樣品不符合規定或是會對儀器設備造成危害，無條件取消該次預約。(If the sample does not meet the regulations or will cause harm to the equipment, the appointment will be cancelled unconditionally.)◎若因申請人提供之樣品造成操作人員傷害，或是儀器設備故障，申請人均應負賠償責任。(If the sample provided by the applicant causes injury to the operator or equipment failure, the applicant shall be liable for compensation.)◎聯絡信箱(Contact e-mail)： ◎申請人簽名(signature of Applicant)： ◎指導教授/主管簽名(Advisor/Supervisor Signature)： ◎日期(Date)： 年(Y) 月(M) 日(D) |